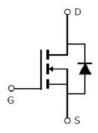


Main Product Characteristics:

V _{DSS}	100V
R _{DS} (on)	2.9mΩ (typ.)
I _D	120A





TO-263 (D2PAK)

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V ①	120	^
I _{DM}	Pulsed Drain Current ②	480	Α
P _D @T _C = 25°C	Power Dissipation ③	179	W
V _{DS}	Drain-Source Voltage	100	V
V _{GS}	Gate-to-Source Voltage	± 20	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

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Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	_	0.7	°C/W

Electrical Characterizes @T_A=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	100	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
R _{DS(on)}	Static Drain-to-Source on-resistance	_	2.9	4	mΩ	V _{GS} =10V,I _D =50A
V _{GS(th)}	Gate threshold voltage	2.5	_	3.5	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
I _{DSS}	Drain-to-Source leakage current	_	_	1	μA	V _{DS} =100V,V _{GS} = 0V
	Cata ta Causaa famusand la alcana	_	_	100	^	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -20V
Qg	Total gate charge	_	65	_		I _D = 50A,
Q _{gs}	Gate-to-Source charge	_	20	_	nC	V _{DS} =50V,
Q _{gd}	Gate-to-Drain("Miller") charge	_	14	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	20	_)/ 40)/
tr	Rise time	_	20	_		V _{GS} =10V,
t _{d(off)}	Turn-Off delay time	_	38	_	ns	$R_{GEN}=2.5\Omega$ $I_D=50A$
t _f	Fall time	_	10	_		
C _{iss}	Input capacitance	_	3785	_		V _{GS} = 0V
Coss	Output capacitance	_	990	_	pF	V _{DS} = 50V
Crss	Reverse transfer capacitance	_	55	_		f = 1MHz

Source-Drain Ratings and Characteristics

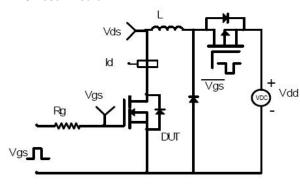
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			120	_	MOSFET symbol
Is	(Body Diode)	_	_	120	A	showing the
	Pulsed Source Current			480	^	integral reverse
I _{SM}	(Body Diode)		A	p-n junction diode.		
V _{SD}	Diode Forward Voltage	_	_	1.2	V	I _S =20A, V _{GS} =0V
trr	Reverse Recovery Time	_	54	_	ns	1 - 50 A di/dt-400 A / · · -
Qrr	Reverse Recovery Charge	_	90	_	nC	ls=50A,di/dt=100A/us

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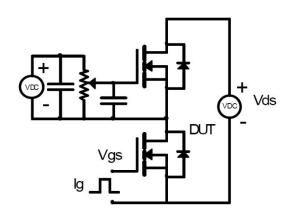


Test Circuits and Waveforms

EAS Test Circuit:

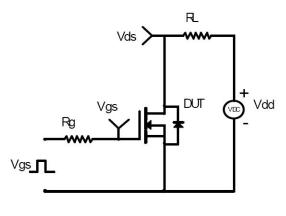


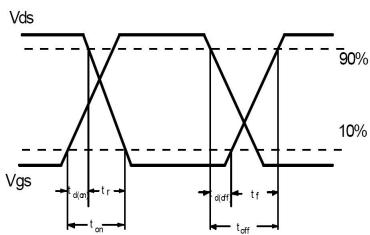
Gate Charge Test Circuit:



Switching Time Test Circuit:

Switching Waveforms:





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Notes:

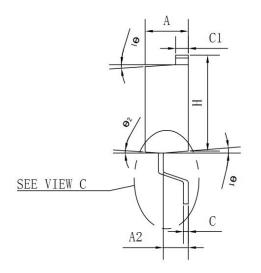
- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- $\ \ \,$ The power dissipation P_D is based on max. junction temperature, using junction-to-case thermal resistance.

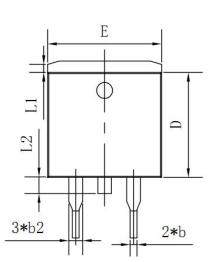


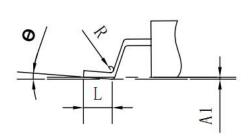


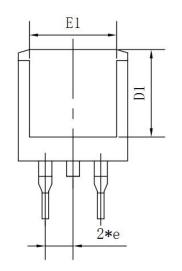
Mechanical Data:

TO-263 Package Outline (Unit:mm)
Option 1









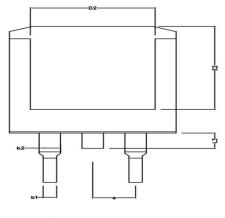
SYMBOL	MIN	NOM	MAX
Α	4. 35	4. 47	4. 60
A1	0. 09	0.10	0.11
A2	2. 30	2. 40	2. 50
Ъ	0.70	0.80	1.00
Ь2	1. 25	1.36	1. 38
С	0. 45	0.50	0. 55
C1	1. 29	1.30	1. 31
D	9. 10	9. 20	9. 30
D1	7. 90	8.00	8. 10
Е	9.85	10.00	10. 20
E1	7. 90	8.00	8. 10
Н	15. 30	15. 50	15. 70
е	-	2. 54	
L	2. 34	2. 54	2. 74
L1	1.00	1. 10	1. 20
L2	1. 30	1.40	1.50
R	0. 24	0.25	0. 26
Θ	0°	4°	8°
0 1	4"	7°	10°
Θ2	0°	3°	6°

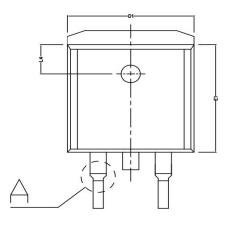
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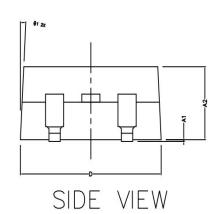




Option 2



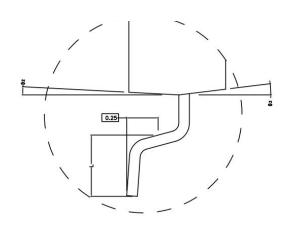




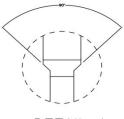
BOTTOM VIEW

B

SIDE VIEW







DETAIL A

101.00	MIN	NORMAL	MAX			
A1	0.020	_	0.200			
A2	4.470	4.570	4.670			
A3	2.300	2.350	2.400			
b1	0.750	-	0.850			
b2	1.220		1.320			
c1	0.500	-	0.550			
c2	1.300	-	1.350			
D	9.780	9.880	9.980			
D1		9.880REF				
D2		7.400REF	65			
E	14.900	15.100	15.300			
E1	9.100	9.200	9.300			
E2		8.100REF				
е		2.540REF				
L	2.100	2.300	2.500			
L2	1.025		1.375			
L3	1.300	1,500	1.700			
L4	2.400	2.500	2.600			
θ1	3. TABE					
θ2	3° TYPE					
θ3	7° TYPE					
04	7° TYPE					
θ	0 ~ 8*					

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